


<b>Search Notes</b>  	<b>Application/Control No.</b>  10531930	<b>Applicant(s)/Patent Under Reexamination</b>  DE WIT ET AL.
	<b>Examiner</b>  TUAN H NGUYEN	<b>Art Unit</b>  2618

SEARCHED			
Class	Subclass	Date	Examiner
455	41.2,66.1,425,426.1.	11/17/2008	T.N

SEARCH NOTES		
Search Notes	Date	Examiner
All searches are on EAST data base.	11/17/2008	T.N

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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